Substitute for form 1449A/PTO	Under the Peperwork Raduction Act of 1996, no persons are required to respond to a collection of information unfees it contains a valid OMS control number. Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY ARPLICANT (Use as many style) modesses APR 2 9 2005 Sheet 1 of 1	Application Number	10/661,379	
	Filing Date	September 12, 2003	
	First Named Inventor	Yin, Zhiping	
	Group Art Unit	2829	
	Examiner Name	Wilson, Christian	
	Attorney Docket No: 3	03.864US1	

. . . .

US PATENT DOCUMENTS					
Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate	
10	US-2005/0056835A1	03/17/2005	Yin, Z., et al.	02/27/2004	
	US-2005/0056940A1	03/17/2005	Sandhu, G. S., et al.	09/12/2003	
	US-5,800,878	09/01/1998	Yao, Xiang Y.	10/24/1996	
	US-6,035,803	03/14/2000	Robles, Stuardo, et al.	09/29/1997	
	US-6,211,065	04/03/2001	Xi, Ming, et al.	10/10/1997	
	US-6,291,334	09/18/2001	Somekh, Somekh	12/19/1997	
	US-6,323,119	11/27/2001	Xi, Ming, et al.	10/10/1997	
	US-6,423,384	07/23/2002	Khazeni, Kasra, et al.	06/25/1999	
	US-6,508,911	01/21/2003	Han, Nianci, et al.	08/16/1999	
	US-6,541,397	04/01/2003	Bencher, Christopher D.	03/29/2002	
	US-6,551,941	04/22/2003	Yang, Chan-syun D., et al.	02/22/2001	
	US-6,573,030	06/03/2003	Fairbairn, Kevin, et al.	06/08/2000	
	US-6,624,064	09/23/2003	Sahin, Turgut, et al.	10/10/1997	
	US-6,627,532	09/30/2003	Gaillard, Frederic	10/05/2000	
1	US-6,668,752	12/30/2003	Yao, Xiang Y.	06/16/1998	
	US-6,780,753	08/24/2004	Latchford, Ian S., et al.	05/31/2002	
	US-6,784,119	08/31/2004	Gaillard, Frederic, et al.	07/31/2003	
	US-6,821,571	11/23/2004	Huang, Judy	06/18/1999	
	US-6,841,341	01/11/2005	Fairbairn, Kevin, et al.	12/17/2002	
	US-6,852,647	02/08/2005	Bencher, Christopher D.	03/07/2003	
137	US-6,875,687	04/05/2005	Weidman, Timothy	10/18/2000	

		FOREIGN PATEN	IT DOCUMENTS	
Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	T²
$\exists \Omega$	WO-2005/034216A1	04/14/2005	Sandhu, G. S., et al.	
22	WO-2005/034229A1	04/14/2005	Yin, Z., et al.	
Jan .	WO-2004/012246A2	02/05/2004	Bonser, Douglas J., et al.	

EXAMINER DATE CONSIDERED 3/3/06

PTC/SB/06A(10-01)
Approved for use through 10/31/2002, Oka9 651-0031
US Peters & Tredemarh Office: U.S. DEPARTMENT OF COMMERCES
on of information unless it contains a valid CMIB control number. Substitute of form 1449A/PTO
INFORMATION DISCLOSURE
EMENT BY APPLICANT
as many sheets as nocessary) Complete if Known **Application Number** 10/661,379 Filing Date September 12, 2003 **First Named Inventor** Yin, Zhiping 1756 **Group Art Unit** Rosasco, Stephen **Examiner Name** Attorney Docket No: 303.864US1 Sheet 1 of 1

US PATENT DOCUMENTS				
Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
430	US-2003/0198814 A1	10/23/2003	Khieu, S. S., et al.	04/23/2002
2	US-2004/0092098 A1	05/13/2004	Sudijono, J., et al.	11/08/2002
AL	US-2006/0001175 A1	01/05/2006	Sandhu, G. S.	08/30/2005
20	US-2006/0003237 A1	01/05/2006	Yin, Z., et al.	08/30/2005
XZ	US-5,470,661	11/28/1995	Bailey, F. D., et al.	01/07/1993
20	US-6,795,636	09/21/2004	Cronk, B. J., et al.	03/05/2000

FOREIGN PATENT DOCUMENTS				
Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	T²

	OTHE	R DOCUMENTS NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No 1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T*
A		CHEN, Z. Y., et al., "Optical Constants of Tetrahedral Amorphous Carbon Films in the Infrared Region and at a Wavelength of 633 nm", <u>Journal of Applied Physics</u> , Vol. 87 (9), American Institute of Physics, (May 1, 2000),4268	
A		HE, X., et al., "Characterization and Optical Properties of Diamondlike Carbon Prepared by Electron Cyclotron Resonance Plasma", Journal of Materials Research, vol. 14 (3), (Mar. 1999), 1055	
A		LIDE, D. R., et al., "Physical Constants of Organic Compounds", <u>CRC Handbook of Chemistry and Physics, Internet Version 2005, http://www.hbcpnetbase.com</u> , (2005),12-157	
Tar		ZHOU, X. T., et al., "Deposition and Properties of a-C:H films on Polymethyl Methacrylate by electron Cyclotron Resonance Microwave Plasma Chemical Vapor Deposion Method", <u>Surface and Coatings Technology</u> , 123, www.elsevier.nl/locate.surfcoat,(2000),273-277	

Zusco **EXAMINER** DATE CONSIDERED